

Docket No. 239720US90CONT



IFW/18
CC

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Toshio TSUKAKOSHI

SERIAL NO: 10/608,032

GAU: 2877

FILED: June 30, 2003

EXAMINER: STOCK JR. G.

FOR: IMAGE FORMING CHARACTERISTICS MEASURING METHOD, IMAGE FORMING CHARACTERISTICS ADJUSTING METHOD, EXPOSURE METHOD AND APPARATUS, PROGRAM AND STORAGE MEDIUM, AND DEVICE MANUFACTURING METHOD

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☒ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☒ Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

10/27/2004 EAREGAY1 00000065 10608032

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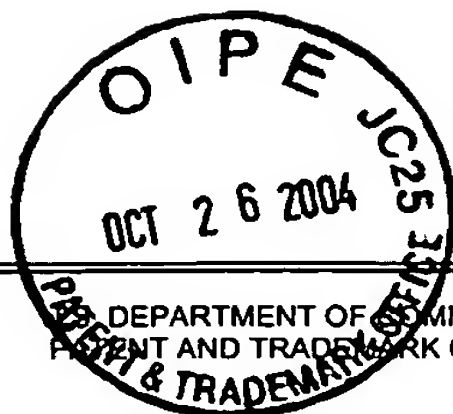
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Respectfully submitted,

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Form PTO 1449
(Modified)DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
239720US90CONTSERIAL NO.
10/608,032

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Toshio TSUKAKOSHIFILING DATE
June 30, 2003GROUP
2877

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	6,078,554	06/20/2000	OOTAKI, et al.			
	AB	6,118,535	09/12/2000	GOLDBERG, et al.			
	AC	6,100,978	08/08/2000	NAULLEAU, et al.			
	AD	2002/0001071 A1	01/03/2002	NOMURA, et al.			
	AE	5,754,299	05/19/1998	SUGAYA, et al.			
	AF	6,329,112	12/11/2001	FUKUDA, et al.			
	AG	5,807,647	09/15/1998	HASHIMOTO			
	AH	5,321,493	06/14/1994	KAMON			
	AI	4,786,166	11/22/1988	KROKO			
	AJ	5,898,501	04/27/1999	SUZUKI, et al.			
	AK	6,245,470	06/12/2001	KAMON			
	AL	6,268,903	07/31/2001	CHIBA, et al.			
	AM	6,459,480	10/01/2002	KYE			
	AN	6,570,143	05/27/2003	NEIL, et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	198 20 785.9 A1	10/21/1999	Germany		x
	AP	2000-146757	05/26/2000	Japan (w/ English abstract and machine translation)	x	
	AQ	2000-266640	09/29/2000	Japan (w/ English abstract and machine translation)	x	
	AR	WO 00/55890	09/21/2000	WIPO (w/ English abstract)		x
	AS	2001-230193	08/24/2001	Japan (w/ English abstract and machine translation)	x	
	AT	1 355 140 A1	10/22/2003	Europe (corresponding to U.S. Application 10/608,032)		
	AU	1 359 608 A1	11/05/2003	Europe		
	AV	WO 02/50506 A1	06/27/2002	WIPO (w/ English abstract)		x
	AW	0 267 721	05/18/1988	Europe		
	AX	0 338 200	10/25/1989	Europe		
	AZ					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	BA	Winter 1998 MICROLITHOGRAPHY WORLD pages 11-20 Authors: Donis G. Flagello and Bernd Geh Title: "The influence of lens aberrations in lithography"
	BB	Journal of Vacuum Science & Technology B: Microelectronics Processing and Phenomena, American Vacuum Society, New York, NY, US, vol. 16, no. 6, November 1998 (1998-11) pages 3435-3439 Authors: K. Goldberg, et al. Title: "High-accuracy interferometry of extreme ultraviolet lithographic optical system"
	BC	<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



LIST OF RELATED CASES

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Patent Appl. Publication No.</u>	<u>Inventor/ Applicant</u>
239720US90 CONT*	10/608,032	06/30/03	2004-0059444	TSUKAKOSHI
256663US90 CONT	10/901,209	07/29/04		SHIMIZU et al.